Reference (PR No. 1000019966) RFx No. 6100000754

Technical Specifications of Spare parts of Spare parts of Element of Energy Dispersive X Ray Spectroscopy (EDS) System

Part No	Description
PV6500	**Element EDS System, manual slide with APEX Standard Software**
	Element EDS System with Element Silicon Drift Detector with manual slide and APEX™ Standard Software
	Element Silicon Drift Detector with manual slide • Liquid Nitrogen free with integrated Peltier cooling system. • Typical resolution of 129 eV, measured at Mn Kα, measured according to ISO 15632:2012. • 30 mm² SDD chip. • Silicon Nitride window with honeycomb grid: increased transmissivity; increased light element sensitivity; plasma cleaner compatible. • Capable of handling throughput of >300kcps. • Multiple amp times available. • Vacuum encapsulated module: better low energy sensitivity, lower power draw. • 10 eV/channel resolution for spectral collection. • Manual Slide. • Single mains plug with universal input voltage The detector conforms to ISO 15632:2012 specifying performance at productive count rates

	APEX™ Standard Software An intuitive software package for fast and accurate elemental analysis with an easy-to-use user interface for EDS data collection, analysis, mapping, and reporting. The APEX™ Software Suite streamlines analysis and facilitates workflow for material characterization.
	Element DPP Support Box
	Beam control and data acquisition package provides digital control of the electron microscope beam and acquisition video signal with 16-bit resolution. • Advanced signal acquisition electronics for SDD drive high throughput and stable resolution performance • User-selectable processing times allow collection tailored to application-specific needs. Faster processing times drive higher throughput. Longer times improve resolution performance. • 5-level fast discriminator settings offer better pile-up rejection and reduce sum peaks
	Electron Microscope interface for Beam Control package.
	Stage Software enables control of microscope stage (X, Y and Z axes) through EDAX software. Offered if access controls are available from electron microscope.
	Column Software enables control of reading and changing of electron microscope column parameters through EDAX software. Offered if capability available on electron microscope.

	Z2-i7 Analyzer Specifications: • Intel i7-8700K (3.7 GHz, Max: 4.7 GHz, 6-Core) • Windows 10 Professional 64-bit Operating System • 16 GB DDR4-1600 MHz (2 x 8 GB) • 2 TB 7200 RPM SATA Hard Drive • LG DVD SATA Reader/Writer • Microsoft Office 2016 Home & Business • 4 PCIe Slots (No Motherboard PCI Slots) • HP Serial Port Adapter Kit (optional) • Rear Panel 4 USB 3.1, Front Panel 2 USB 3.1 • 1 Gigabit Motherboard Ethernet
	24" Widescreen Flat Panel LCD Monitor (for Element)
	Installation